



## VORLESUNG WS 2015/2016 PME-3.3

# Physical Characterization of Organic and Organic-Inorganic Thin Films

Prof. Dr. E. Zschech, Prof. Dr. M. Stamm

Termin: Mittwoch, 1. DS (07:30 – 09:00 Uhr) Konferenzsaal, IPF, Hohe Str. 6 , Beginn: 14.10.2015

14.10.2015	Nanostructures and organic electronics	Prof. Zschech/ Prof. Stamm
21.10.2015	Mechanical characterization of organic/polymeric materials; basics of contact mechanics and nanoindentation methods	Dr. Kopycinska-Müller
28.10.2015	Atomic force microscopy – the principle of surface characterization; Mechanical characterization of organic materials on nanoscale	Dr. Kopycinska-Müller
04.11.2015	Multi-scale characterization of hybrid organic-inorganic thin films	Prof. Zschech
11.11.2015	X-ray microscopy and tomography – Potentials, limitations new developments	Prof. Zschech
25.11.2015	Nanoscale characterization of materials by combined use of TEM and Atom Probe Tomography	Prof. Zschech
02.12.2015	Electron microscopy of soft matter surfaces and organic thin films (TEM, SEM, FIB, EELS, EDX) – part 1	Dr. Formanek
09.12.2015	Electron microscopy of soft matter surfaces and organic thin films (TEM, SEM, FIB, EELS, EDX) – part 2	Dr. Formanek
16.12.2015	Chemical functionalization and characterization of interfaces between materials for organic electronics (adhesion, wetting, reflectometry, GISAXS, AFM)	Prof. Stamm
06.01.2016	Chemical analysis of surfaces and organic thin films (XPS, AES, SIMS)	Dr. Simon
13.01.2016	Ellipsometry for organic thin films and surfaces	Dr. Eichhorn
20.01.2016	Spectroscopic and structural characterization of organic thin films and surfaces (IR, Raman, SERS, AFM, SEM, Scatt.)	Prof. Stamm
27.01.2016	Characterization of single and collective plasmonic resonances	Dr. König
03.02.2016	Klausur	Prof. Zschech / Prof. Stamm